SN54F37, SN74F37
QUADRUPLE 2-INPUT POSITIVE-NAND BUFFERS

D3206, JANUARY 1989—REVISED APRIL 1989

- **Package Options Include Plastic "Small Outline" Packages, Ceramic Chip Carriers, and Standard Plastic and Ceramic 300-mil DIPs**
- **Dependable Texas Instruments Quality and Reliability**

description

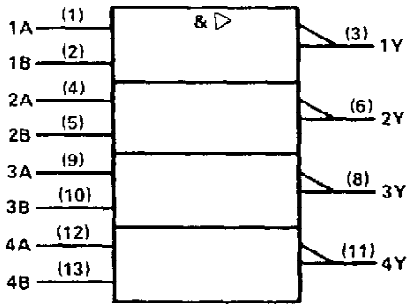
These devices contain four independent 2-input NAND buffer gates. They perform the Boolean functions $Y = \overline{A \cdot B}$ or $Y = \overline{A} + \overline{B}$ in positive logic.

The SN54F37 is characterized for operation over the full military temperature range of −55°C to 125°C. The SN74F37 is characterized for operation from 0°C to 70°C.

FUNCTION TABLE (each gate)

INPUTS		OUTPUT
A	B	Y
H	H	L
L	X	H
X	L	H

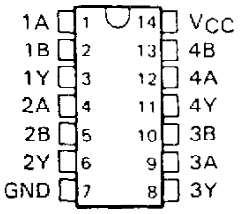
logic symbol†



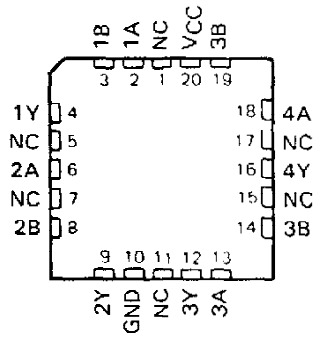
†This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for D, J, and N packages.

SN54F37 . . . J PACKAGE
SN74F37 . . . D OR N PACKAGE
(TOP VIEW)

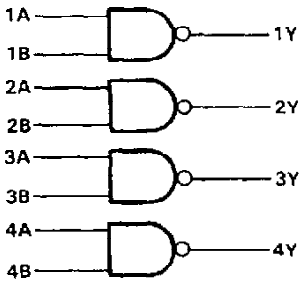


SN54F37 . . . FK PACKAGE
(TOP VIEW)



NC – No internal connection

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V_{CC} . . . . . −0.5 V to 7 V
Input voltage† . . . . . −0.5 V to 7 V
Input current . . . . . −30 mA to 5 mA
Voltage applied to any output in the high state . . . . . −0.5 V to V_{CC}
Current into any output in the low state . . . . . 128 mA
Operating free-air temperature range: SN54F37 . . . . . −55°C to 125°C
SN74F37 . . . . . 0°C to 70°C
Storage temperature range . . . . . −65°C to 150°C

†The input voltage ratings may be exceeded provided the input current ratings are observed.

recommended operating conditions

		SN54F37			SN74F37			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
V_{CC}	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
V_{IH}	High-level input voltage	2			2			V
V_{IL}	Low-level input voltage			0.8			0.8	V
I_{IK}	Input clamp current			−18			−18	mA
I_{OH}	High-level output current			−15			−15	mA
I_{OL}	Low-level output current			48			64	mA
T_A	Operating free-air temperature	−55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		SN54F37			SN74F37			UNIT
			MIN	TYP†	MAX	MIN	TYP†	MAX	
V_{IK}	V_{CC} = 4.5 V,	I_I = −18 mA		−0.73	−1.2			−1.2	V
V_{OH}	V_{CC} = 4.5 V,	I_{OH} = −1 mA	2.5	3.4		2.5	3.4		V
	V_{CC} = 4.5 V,	I_{OH} = −15 mA	2			2			
	V_{CC} = 4.75 V,	I_{OH} = −1 mA				2.7			
V_{OL}	V_{CC} = 4.5 V	I_{OL} = 48 mA		0.35	0.5				V
		I_{OL} = 64 mA					0.40	0.55	
I_I	V_{CC} = 5.5 V,	V_I = 7 V			0.1			0.1	mA
I_{IH}	V_{CC} = 5.5 V,	V_I = 2.7 V			20			20	μA
I_{IL}	V_{CC} = 5.5 V,	V_I = 0.5 V			−0.6			−0.6	mA
I_{OS}‡	V_{CC} = 5.5 V,	V_O = 0	−100		−225	−100		−225	mA
I_{CCH}	V_{CC} = 5.5 V,	V_I = 0		3	6		3	6	mA
I_{CCL}	V_{CC} = 5.5 V,	V_I = 4.5 V		23	33		23	33	mA

switching characteristics (see Note 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V_{CC} = 5 V, C_L = 50 pF, R_L = 500 Ω, T_A = 25°C			V_{CC} = 4.5 V to 5.5 V, C_L = 50 pF, R_L = 500 Ω, T_A = MIN to MAX§			UNIT
			'F37			SN54F37		SN74F37	
			MIN	TYP†	MAX	MIN	MAX	MIN	MAX	
t_{PLH}	A or B	Y	1.5	3.1	5.5	1	7	1.5	6.5	ns
t_{PHL}			1	2.1	4.5	1	6	1	5	

†All typical values are at V_{CC} = 5 V, T_A = 25°C.
‡Not more than one output should be shorted at a time and the duration of the short circuit should not exceed one second.
§For conditions shown as MIN or MAX, use the appropriate value specified under Recommended Operating Conditions.
NOTE 1: Load circuits and waveforms are shown in Section 1 of the *F Logic Data Book, 1989.*

IMPORTANT NOTICE

Texas Instruments (TI) reserves the right to make changes to its products or to discontinue any semiconductor product or service without notice, and advises its customers to obtain the latest version of relevant information to verify, before placing orders, that the information being relied on is current.

TI warrants performance of its semiconductor products and related software to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

Certain applications using semiconductor products may involve potential risks of death, personal injury, or severe property or environmental damage ("Critical Applications").

TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, INTENDED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT APPLICATIONS, DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS.

Inclusion of TI products in such applications is understood to be fully at the risk of the customer. Use of TI products in such applications requires the written approval of an appropriate TI officer. Questions concerning potential risk applications should be directed to TI through a local SC sales office.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards should be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance, customer product design, software performance, or infringement of patents or services described herein. Nor does TI warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used.